

${}^1\text{H}({}^{27}\text{Si}, {}^{26}\text{Si}\gamma)$  2012Ch18

Type	Author	History	Citation	Literature Cutoff Date
Full Evaluation	M. S. Basunia and A. M. Hurst		NDS 134, 1 (2016)	1-Feb-2016

Also  ${}^{12}\text{C}({}^{27}\text{Si}, {}^{26}\text{Si}\gamma)$ .

An 84.3-MeV/nucleon  ${}^{27}\text{Si}$  beam bombarded a 180-mg/cm<sup>2</sup> (C<sub>3</sub>H<sub>3</sub>)<sub>n</sub> target at the National Superconducting Cyclotron Laboratory (NSCL). The  ${}^{27}\text{Si}$  secondary beam was produced by fragmentation of a 150-MeV/nucleon  ${}^{36}\text{Ar}^{18+}$  primary beam on a 940-mg/cm<sup>2</sup>  ${}^9\text{Be}$  target and delivered to the S800 spectrograph using the A1900 fragment separator with an intensity of  $\approx 10^6$  pps. Measured energy loss and residual energy of the  ${}^{26}\text{Si}$  recoils using a segmented ionization chamber and plastic scintillator, respectively. The time of flight (TOF) between a diamond strip detector and the plastic scintillator for the  ${}^{26}\text{Si}$  recoils was also measured.  $\gamma$  rays measured with the Segmented Germanium Array (SeGA) comprising 17 high-purity germanium crystals. Measured particle- $\gamma$  and  $\gamma$ - $\gamma$  coincidences. Deduced levels and  $E_\gamma$ .

 ${}^{26}\text{Si}$  Levels

E(level) <sup>†</sup>	J $\pi$ <sup>‡</sup>	E(level) <sup>†</sup>	J $\pi$ <sup>‡</sup>	E(level) <sup>†</sup>	J $\pi$ <sup>‡</sup>	E(level) <sup>†</sup>	J $\pi$ <sup>‡</sup>
0.0	0 <sup>+</sup>	3753 5	3 <sup>+</sup>	4802 14	4 <sup>+</sup>	5510 8	4 <sup>+</sup>
1796.1 10	2 <sup>+</sup>	4135 20	2 <sup>+</sup>	4810 10	(2 <sup>+</sup> )	5658 20	1 <sup>+</sup>
2785 4	2 <sup>+</sup>	4190 7	3 <sup>+</sup>	5144 12	2 <sup>+</sup>		
3329 7	0 <sup>+</sup>	4443 6	4 <sup>+</sup>	5283 6	4 <sup>+</sup>		

<sup>†</sup> From least-squares fit (by evaluators) to  $E_\gamma$ . 1334 $\gamma$  from the 5510-keV level not used in fit due to poor agreement with level scheme.

<sup>‡</sup> From angular distribution measurements in 2007Se02.

 $\gamma({}^{26}\text{Si})$ 

$E_\gamma$	$E_i(\text{level})$	J $\pi$ <sub>i</sub>	$E_f$	J $\pi$ <sub>f</sub>	Comments
839 4	5283	4 <sup>+</sup>	4443	4 <sup>+</sup>	
968 4	3753	3 <sup>+</sup>	2785	2 <sup>+</sup>	
987 4	2785	2 <sup>+</sup>	1796.1	2 <sup>+</sup>	
1067 5	5510	4 <sup>+</sup>	4443	4 <sup>+</sup>	
1334 6	5510	4 <sup>+</sup>	4190	3 <sup>+</sup>	$E_\gamma$ : Poor fit; level-energy difference implies $E_\gamma=1320(11)$ keV.
1405 6	4190	3 <sup>+</sup>	2785	2 <sup>+</sup>	
1533 <sup>†</sup> 7	3329	0 <sup>+</sup>	1796.1	2 <sup>+</sup>	$E_\gamma$ : Doublet.
1533 <sup>†</sup> 7	5283	4 <sup>+</sup>	3753	3 <sup>+</sup>	$E_\gamma$ : Doublet.
1652 8	4443	4 <sup>+</sup>	2785	2 <sup>+</sup>	
1796	1796.1	2 <sup>+</sup>	0.0	0 <sup>+</sup>	$E_\gamma$ : Used for calibration.
1959 9	3753	3 <sup>+</sup>	1796.1	2 <sup>+</sup>	
2025 9	4810	(2 <sup>+</sup> )	2785	2 <sup>+</sup>	
2359 11	5144	2 <sup>+</sup>	2785	2 <sup>+</sup>	
2648 12	4443	4 <sup>+</sup>	1796.1	2 <sup>+</sup>	
2787 13	2785	2 <sup>+</sup>	0.0	0 <sup>+</sup>	
3006 14	4802	4 <sup>+</sup>	1796.1	2 <sup>+</sup>	
3500 17	5283	4 <sup>+</sup>	1796.1	2 <sup>+</sup>	
3862 20	5658	1 <sup>+</sup>	1796.1	2 <sup>+</sup>	
4135 20	4135	2 <sup>+</sup>	0.0	0 <sup>+</sup>	

<sup>†</sup> Multiply placed.

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## Level Scheme

